

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	69	(CMOS complementary metal oxide semi\$1conductor complementary symmetry metal oxide semi\$1conductor) AND transient AND time AND integral AND current AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas. "326".clas. "714".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 10:17
L3	58	(test pattern test criteri\$2) AND (points data sets measurements) AND transient AND current AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas. "326".clas. "714".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 10:35
L4	85	(test pattern test criteri\$2 test set) AND (points data sets measurements) AND transient AND current AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas. "326".clas. "714".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 11:06
L5	26	abnormal\$3 AND (test pattern test criteri\$2 test set) AND (points data sets measurements) AND transient AND current AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas. "326".clas. "714".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 11:07
L6	56	fault\$3 AND (test pattern test criteri\$2 test set) AND (points data sets measurements) AND transient AND current AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas. "326".clas. "714".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 11:08

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L7	23	fault\$3 AND abnormal\$3 AND (test pattern test criteri\$2 test set) AND (points data sets measurements) AND transient AND current AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas. "326".clas. "714".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 11:08
L8	23	fault\$3 AND abnormal\$3 AND (test pattern test criteri\$2 test set) AND (points data sets measurements) AND transient AND current AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas. "326".clas. "714".clas. "73".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 11:13
L9	8	"5943346".pn. "5505539".pn. "5864566".pn. "4646299".pn.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/19 11:16
S1	109	defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:48
S2	63	analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:49
S3	0	transient power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:50
S4	51	power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 17:00

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S5	40	fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S6	40	current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:50
S7	37	potential AND current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S8	9	voltage AND current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S9	9	current AND voltage AND current AND fault AND power supply AND analysis AND defect AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/21 16:51
S10	2	"6043672".pn.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2007/08/22 09:34
S11	11	current AND voltage AND current AND fault AND power supply AND analysis AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 14:56

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S12	27	current AND voltage AND fault AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 14:57
S13	11	fault location AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:23
S14	14	(fault location defect\$3 signal\$1) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:23
S15	5	(("IC" OR integrated circuit) (semiconductor OR semi-conductor)) AND (fault location defect\$3 signal\$1) AND ("713".clas. OR "726".clas. OR "380".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:34
S16	189433	(ishida.in. yamaguchi.in. hashimoto.in.)	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:35
S17	36	(ishida.in. yamaguchi.in. hashimoto.in.) AND fault AND defect\$3 AND analysis AND ("IC" integrated circuit semi\$1conductor)	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:36
S18	205	(("IC" OR integrated circuit) (semiconductor OR semi-conductor)) AND (fault location defect\$3 signal\$1) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:41
S19	698	(fault location defect\$3 signal\$1) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd< "20000404" or @ad< "20000404" or @prad< "20000404" or @rlad< "20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:41

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S20	278	current AND voltage AND fault AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:41
S21	77	current AND voltage AND current AND fault AND power supply AND analysis AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:42
S22	8	signal\$1 AND fault AND current AND voltage AND (fault location defect\$3 signal\$1) AND power supply AND analysis AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:43
S23	8	signal\$1 AND fault\$1 AND current AND voltage AND (fault location defect\$3 signal\$1) AND power supply AND analysis AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:43
S24	26	(ishida.in. yamaguchi.in. hashimoto.in.) AND fault AND defect\$3 AND analysis AND ("IC" integrated circuit) AND (semi\$1conductor)	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:48
S25	66	(stor\$3 memory medium media) AND current AND voltage AND current AND fault AND power supply AND analysis AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20000404" or @ad<"20000404" or @prad<"20000404" or @rlad<"20000404")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 15:59

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S26	2	"6043672".pn.	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2008/07/28 16:40
S27	64	transient AND voltage AND current AND fault AND power supply AND analysis AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/01/08 15:32
S28	20	transient current AND voltage AND current AND fault AND power supply AND analysis AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/01/08 15:49
S29	6	transient current AND time AND integral AND voltage AND current AND fault AND power supply AND analysis AND defect\$3 AND ("IC" OR integrated circuit) AND (semiconductor OR semi-conductor) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/01/08 15:49
S30	13	transient current AND time AND integral AND voltage AND current AND (fault defect\$3) AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:11
S31	8	(CMOS complementary metal oxide semiconductor) AND transient current AND time AND integral AND voltage AND current AND (fault defect\$3) AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:12

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S32	8	(CMOS complementary metal oxide semi\$1conductor complementary symmetry metal oxide semi\$1conductor) AND transient current AND time AND integral AND voltage AND current AND (fault defect\$3) AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:12
S33	6	(CMOS complementary metal oxide semi\$1conductor complementary symmetry metal oxide semi\$1conductor) AND transient AND time AND (sum NEAR integral) AND current AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:15
S34	6	transient AND time AND (sum NEAR integral) AND current AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:16
S35	6	transient AND time AND (sum NEAR integral) AND current AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas. "326".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:16
S36	7	transient AND time AND (sum NEAR integral) AND current AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas. "326".clas. "714".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:16
S37	256	transient AND time AND (sum total tally) AND integral AND current AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas. "326".clas. "714".clas.) AND (@pd<"20040217" or @ad<"20040217" or @prad<"20040217" or @rlad<"20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:17

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S38	56	(CMOS complementary metal oxide semi\$1conductor complementary symmetry metal oxide semi\$1conductor) AND transient AND time AND (sum total talley) AND integral AND current AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas. "326".clas. "714".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:17
S39	10	(CMOS complementary metal oxide semi\$1conductor complementary symmetry metal oxide semi\$1conductor) AND transient AND time AND (sum total talley) AND (time NEAR integral) AND current AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas. "326".clas. "714".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:17
S40	10	(CMOS complementary metal oxide semi\$1conductor complementary symmetry metal oxide semi\$1conductor) AND transient AND tim\$3 AND (sum total talley) AND (time NEAR integral) AND current AND power supply AND analy\$4 AND ("IC" OR integrated circuit) AND ("713".clas. OR "726".clas. OR "380".clas. "324".clas. "326".clas. "714".clas.) AND (@pd< "20040217" or @ad< "20040217" or @prad< "20040217" or @rlad< "20040217")	US-PGPUB; USPAT; USOCR; EPO; DERWENT; IBM_TDB	ADJ	ON	2009/06/18 17:18